

MOS FIELD EFFECT TRANSISTOR μ PA1814

P-CHANNEL MOS FIELD EFFECT TRANSISTOR FOR SWITCHING

DESCRIPTION

The μ PA1814 is a switching device which can be driven directly by a 4 V power source.

The μ PA1814 features a low on-state resistance and excellent switching characteristics, and is suitable for applications such as power switch of portable machine and so on.

FEATURES

- Can be driven by a 4 V power source
- · Low on-state resistance

 $R_{DS(on)1} = 16 \text{ m}\Omega \text{ MAX.} \text{ (Vgs} = -10 \text{ V, Ip} = -3.5 \text{ A)}$

 $R_{DS(on)2} = 24 \text{ m}\Omega \text{ MAX.} \text{ (Vgs} = -4.5 \text{ V, Ip} = -3.5 \text{ A)}$

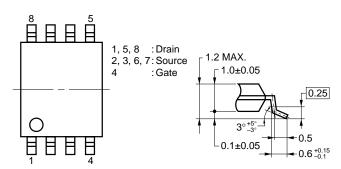
 $R_{DS(on)3} = 27 \text{ m}\Omega \text{ MAX.} \text{ (Vgs} = -4.0 \text{ V, Ip} = -3.5 \text{ A)}$

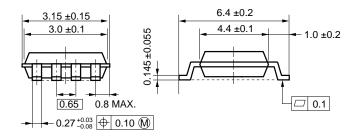
• Built-in G-S protection diode against ESD

ORDERING INFORMATION

PART NUMBER	PACKAGE
μPA1814GR-9JG	Power TSSOP8

PACKAGE DRAWING (Unit:mm)

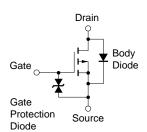




ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

Drain to Source Voltage	VDSS	-30	V
Gate to Source Voltage	Vgss	±20	V
Drain Current (DC)	I _{D(DC)}	±7.0	Α
Drain Current (pulse) Note1	ID(pulse)	±28	Α
Total Power Dissipation Note2	Рт	2.0	W
Channel Temperature	Tch	150	°C
Storage Temperature	T _{stg}	-55 to +150	°C

EQUIVALENT CIRCUIT



Notes 1. PW \leq 10 μ s, Duty Cycle \leq 1 %

2. Mounted on ceramic substrate of 5000 mm² x 1.1 mm

Remark The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

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The mark \bigstar shows major revised points.

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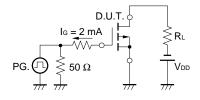
ELECTRICAL CHARACTERISTICS (T_A = 25 °C)

CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	IDSS	Vps = -30 V, Vgs = 0 V			-10	μΑ
Gate Leakage Current	Igss	Vgs = ±20 V, Vps = 0 V			±10	μΑ
Gate Cut-off Voltage	V _{GS(off)}	V _{DS} = -10 V, I _D = -1 mA	-1.0	-1.7	-2.5	٧
Forward Transfer Admittance	yfs	V _{DS} = -10 V, I _D = -3.5 A	3	14		S
Drain to Source On-state Resistance	RDS(on)1	Vgs = -10 V, ID = -3.5 A		12	16	mΩ
	RDS(on)2	$V_{GS} = -4.5 \text{ V}, \text{ ID} = -3.5 \text{ A}$		18	24	mΩ
	RDS(on)3	Vgs = -4.0 V, Ip = -3.5 A		20	27	mΩ
Input Capacitance	Ciss	V _{DS} = -10 V		2180		pF
Output Capacitance	Coss	Vgs = 0 V		658		pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		303		pF
Turn-on Delay Time	td(on)	V _{DD} = −15 V		30		ns
Rise Time	tr	ID = -3.5 A		140		ns
Turn-off Delay Time	td(off)	$V_{GS(on)} = -10 \text{ V}$		97		ns
Fall Time	tr	$R_G = 10 \Omega$		86		ns
Total Gate Charge	QG	V _{DS} = -24 V		38		nC
Gate to Source Charge	Qgs	I _D = -7.0 A		5.9		nC
Gate to Drain Charge	Q _{GD}	Vgs = -10 V		8.5		nC
Diode Forward Voltage	V _F (S-D)	IF = 7.0 A, Vgs = 0 V		0.79		V

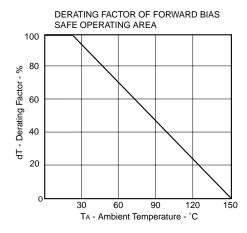
TEST CIRCUIT 1 SWITCHING TIME

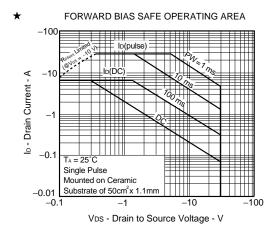
PG. \bigcap RG = 10 Ω \bigcap VDD \bigcap VDD \bigcap VGS \bigcap 10 % \bigcap 10 %

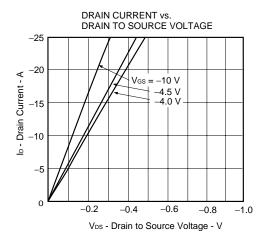
TEST CIRCUIT 2 GATE CHARGE

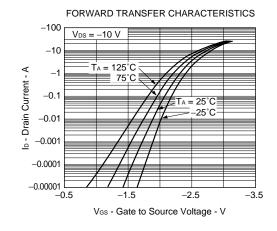


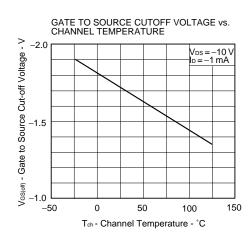
TYPICAL CHARACTERISTICS (TA = 25 °C)

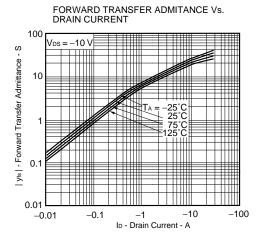


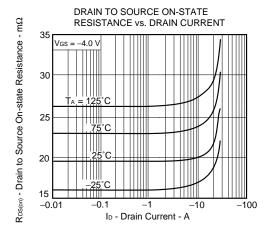


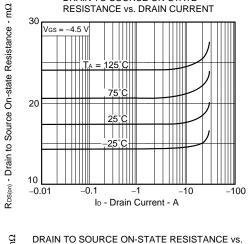






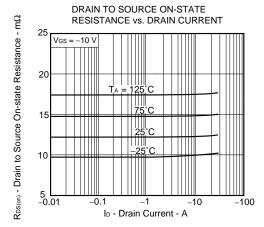


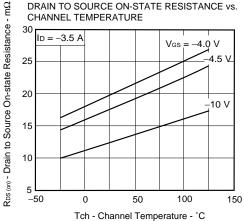


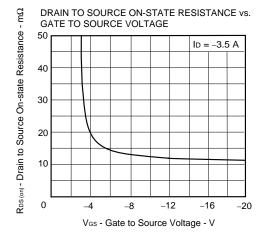


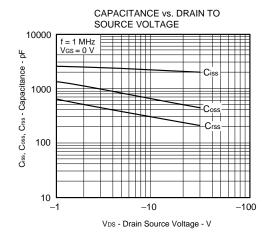
DRAIN TO SOURCE ON-STATE

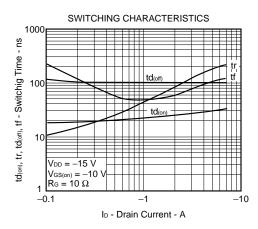
RESISTANCE vs. DRAIN CURRENT

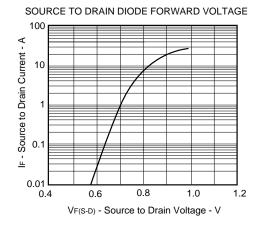


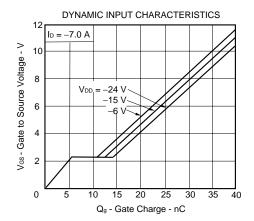




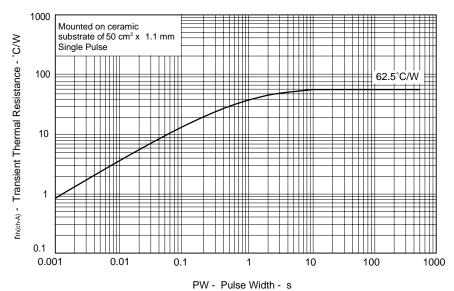








TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH



[MEMO]

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